



## Future Normal in Semiconductor

2025-02-14(금), 15:10-17:10

좌장: 추후업데이트 예정

### A. Interconnect & Package 분과

#### [FD3-A] Advanced Package 2

<p>FD3-A-1 15:10-15:25</p>	<p><b>대기압 기화 플라즈마를 이용한 웨이퍼 본딩 기술</b> Wonyoung Choi, Bumki Moon, Jungshin Lee, Yongjoo Lee, Byeongtak Park, Seung ho Han, Nungpyo Hong, and Kyeongbin Lim Semiconductor R&amp;D Center, Samsung Electronics Co., Ltd.</p>
<p>FD3-A-2 15:25-15:40</p>	<p><b>TEOS SiO<sub>2</sub> Film Deposition Optimization for Increasing Capability and securing TSV robustness of HBM</b> Intae Whoang, Byung Yoon Lim, Kijun Bang, and Sang Un Lee SK hynix</p>
<p>FD3-A-3 15:40-15:55</p>	<p><b>Crystal Plasticity-Based Modeling of the Influence of Microstructures and Grain Boundary Junction Types on the Cu-Cu Bonding Interface</b> Jae-Uk Lee<sup>1</sup>, Hyun-Dong Lee<sup>2</sup>, Sung-Hyun Oh<sup>3</sup>, Jihun Kim<sup>4</sup>, Ki-Beom Kim<sup>5</sup>, Ho-Jin Lee<sup>6</sup>, Yeon-Su Kim<sup>7</sup>, Gyeong-Bim Lim<sup>8</sup>, Sarah-Eunkyoung Kim<sup>9</sup>, Hoo-Jeong Lee<sup>10</sup>, and Eun-Ho Lee<sup>11</sup> <sup>1,2,3,4,10,11</sup>Sungkyunkwan University, <sup>5,7</sup>Sk Hynix, <sup>6,8</sup> Samsung Electronics, <sup>9</sup>Seoul National University of Science of Technology</p>
<p>FD3-A-4 15:55-16:10</p>	<p><b>Drive Circuit for Semiconductor Die Testing and Applications</b> Youngwoo Yoo and Young-Joon Kim Gachon University</p>
<p>FD3-A-5 16:10-16:25</p>	<p><b>An Efficient Standardized Simulation Model for Evaluation of Board Level Reliability in Semiconductor Applications</b> Jaehee An<sup>1</sup>, Sangyul Ha<sup>1</sup>, and Wan-Kyu Choi<sup>2</sup> <sup>1</sup>Department of Semiconductor Engineering, MyongJi University, <sup>2</sup>DRAM Module Solution, SK Hynix</p>
<p>FD3-A-6 16:25-16:40</p>	<p><b>Advanced Cu/Polymer Hybrid bonding for 3D Multi-chip Stacking Process</b> Jihun Kim and Jong Kyoung Park Department of Semiconductor Engineering, Seoul National University of Science and Technology</p>



# 제 32회 한국반도체학술대회

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## *Future Normal in Semiconductor*

<p>FD3-A-7 16:40-16:55</p>	<p><b>Digital Design and DOE-Based Analysis for Optimal Wire Configuration in Diode Modules</b> Na-Yeon Choi<sup>1,2</sup> and Sung-Uk Zhang<sup>1,2</sup> <sup>1</sup>Digital Twin Laboratory, Dong-Eui University, <sup>2</sup>Center for Brain Busan 21 Plus Program</p>
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